Laboratory	**Navanidhi Electronics Pvt. Ltd., Plot No.21, IDA, Mallapur, Hyderabad, Telangana**		
Accreditation Standard	**ISO/IEC 17025: 2005**		
Discipline	**Electrical Testing**	**Issue Date**	**04.07.2014**
Certificate Number	**T-1689**	**Valid Until**	**03.07.2016**
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S.No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	ENVIRONMENTAL TEST FACILITES			
1	**Electrical / Electronic products, sub-assemblies and components**	Vibration (sine) excluding resonance search	MIL-STD-810D (Issue 19 July 1983): Method 514.3 MIL-STD-810G (Issue 31 Oct 2008): Method 514.6 MIL-STD-810F (Issue 01 Jan 2000): Method 514.5 JSS 55555: 2000 Test No. 28 JSS 0256.01: 1992 Test No. 15	5Hz to 2000Hz Acceleration upto 60g Maximum Force: 600kgf
		Vibration (Random)	As above	Random in rms: 10Hz to 2000Hz Asd: 50g, Max Force: 600kgf
		Dry heat / High Temperature	MIL-STD-810D (Issue 19 July 1983): Method 501.2 MIL-STD-810G (Issue 31 Oct 2008): Method 501.5 MIL-STD-810F (Issue 01 Jan 2000): Method 501.4 JSS 55555: 2000 Test No. 17 JSS 0256.01: 1992 Test No. 1	- 70° C to 170ºC (Volume of the Chamber 1 m^3) -70ºC to 180° C (Volume of the Chamber 0.54m x 0.30m x 0.62m)

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Program Manager

Mallika Gope

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S.No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Electrical / Electronic products, sub-assemblies and components	Cold / Low Temperature	MIL-STD-810D (Issue 19 July 1983): Method 502.2 MIL-STD-810G (Issue 31 Oct 2008): Method 502.5 MIL-STD-810F (Issue 01 Jan 2000): Method 500.4 JSS 55555: 2000 Test No. 20 JSS 0256.01: 1992 Test No. 2	- 70° C to 170º C (Volume of the Chamber 1 m³) - 70° C to 180º C (Volume of the Chamber 0.54m x 0.30m x 0.62m)
		Damp Heat Steady State	MIL-STD-810D (Issue 19 July 1983): Method 507.2 MIL-STD-810G (Issue 31 Oct 2008): Method 507.5 MIL-STD-810F (Issue 01 Jan 2000): Method 507.4 JSS 55555: 2000 Test No. 10 JSS 0256.01: 1992 Test No. 4	- 70° C to 170º C (Volume of the Chamber 1 m³) 20% @40 ° C 50% @ 20 °C 70% @ 60° C 85% @ 80 °C 95%@ 45 °C

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S.No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Electrical / Electronic products, sub-assemblies and components	Temperature / Thermal Shock	MIL-STD-810D (Issue 19 July 1983): Method 503.2 MIL-STD-810G (Issue 31 Oct 2008): Method 503.5 MIL-STD-810F (Issue 01 Jan 2000): Method 503.4 JSS 55555: 2000 Test No. 22 JSS 0256.01: 1992 Test No. 5	70 ^{o}C to 170^{o} C (Volume of the Chamber 0.54m x 0.30m x 0.62m)

-X-X-X-X-X-X-X-X-X-X-X-X-X-X-X-

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